

N-Channel Enhancement Mode Power MOSFET

Description

The PT Ì Í ÞÌ \in uses advanced trench technology and design to provide excellent R_{DS(ON)} with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

General Features

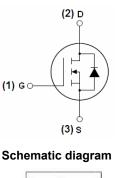
- V_{DS} =85V, I_{D} =80A $R_{DS(ON)}$ < 8.5mΩ @ V_{GS} =10V (Typ:6.8mΩ)
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Special designed for convertors and power controls
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

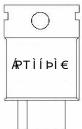
Application

- Power switching application
- Hard switched and High frequency circuits
- Uninterruptible power supply

100% UIS TESTED!

100% AVds TESTED!





Marking and pin assignment



TO-220-3L top view

Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
PTÌÍÞÌ€	PTÌÍÞÌ€	TO-220-3L	-	-	-

Absolute Maximum Ratings (TA=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	85	V
Gate-Source Voltage	V _G s	±20	V
Drain Current-Continuous	I _D	80	Α
Drain Current-Continuous(T _C =100°C)	I _D (100℃)	60	Α
Pulsed Drain Current	I _{DM}	320	Α
Maximum Power Dissipation	P _D	170	W
Peak diode recovery voltage	dv/dt	15	V/ns
Derating factor		1.13	W/℃
Single pulse avalanche energy (Note 5)	E _{AS}	620	mJ
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 175	$^{\circ}\!\mathbb{C}$





Thermal Characteristic

Thermal Resistance, Junction-to-Case(Note 2)	$R_{ heta JC}$	0.88	°C/W	
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Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	•		•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	87	89	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =85V,V _{GS} =0V	-	-	1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	•		•			
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250μA	2	2.85	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =40A	-	6.8	8.5	mΩ
Forward Transconductance	g FS	V _{DS} =25V,I _D =40A	110	-	-	S
Dynamic Characteristics (Note4)	•		•			
Input Capacitance	C _{lss}	\/ -25\/\/ -0\/	-	4400	-	PF
Output Capacitance	Coss	V_{DS} =25V, V_{GS} =0V, F=1.0MHz	-	340	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0WHZ	-	260	-	PF
Switching Characteristics (Note 4)						•
Turn-on Delay Time	t _{d(on)}		-	18	-	nS
Turn-on Rise Time	t _r	VDD=30V,ID=2A,RL=15Ω	-	12	-	nS
Turn-Off Delay Time	t _{d(off)}	,RG=2.5Ω,VGS=10V	-	56	-	nS
Turn-Off Fall Time	t _f		-	15	-	nS
Total Gate Charge	Qg	V 20V/ 1 20A	-	100	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} =30V, I_{D} =30A, V_{GS} =10V	-	20	-	nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	30	-	nC
Drain-Source Diode Characteristics	•		•			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =40A	-	-	1.2	V
Diode Forward Current (Note 2)	Is		-	-	80	Α
Reverse Recovery Time	everse Recovery Time t _{rr} Tj=25°C,I _F =75A,di/dt=100A/µs		-		36	nS
Reverse Recovery Charge	Qrr	Qrr (Note3)			56	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

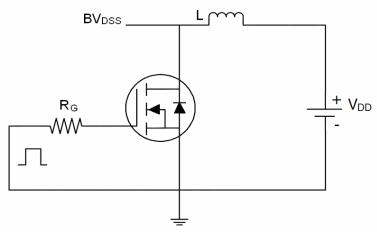
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.

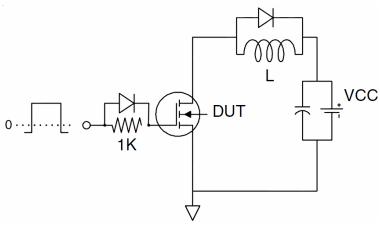
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}\text{C}$,VDD=40V,VG=10V,L=0.5mH,Rg=25 Ω

Test circuit

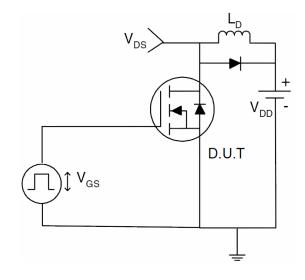
1) E_{AS} test Circuits



2) Gate charge test Circuit:



3) Switch Time Test Circuit:



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)

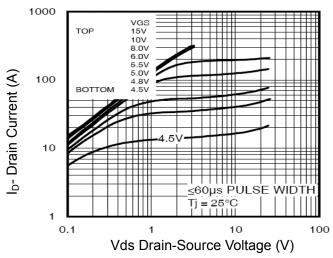


Figure 1 Output Characteristics

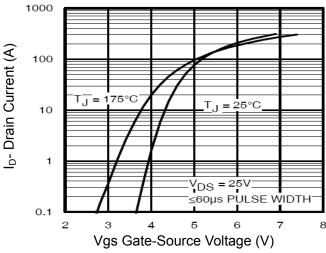


Figure 2 Transfer Characteristics

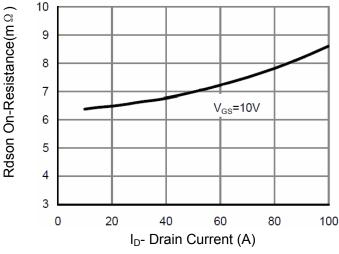


Figure 3 Rdson- Drain Current

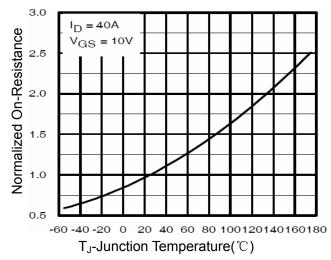


Figure 4 Rdson-JunctionTemperature

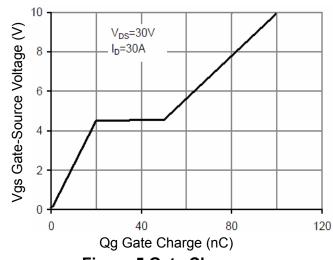


Figure 5 Gate Charge

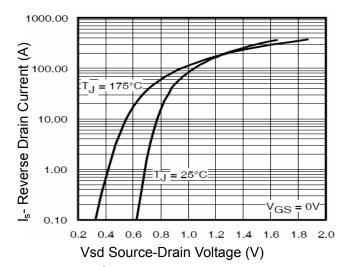


Figure 6 Source- Drain Diode Forward

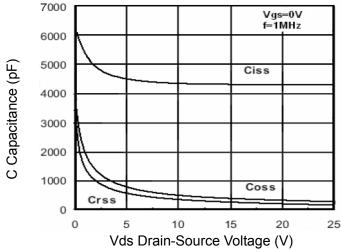


Figure 7 Capacitance vs Vds

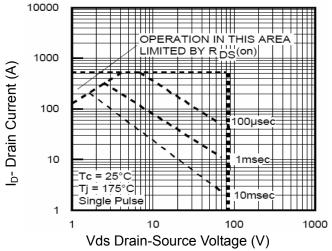


Figure 8 Safe Operation Area

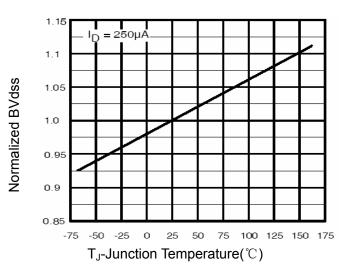


Figure 9 BV_{DSS} vs Junction Temperature

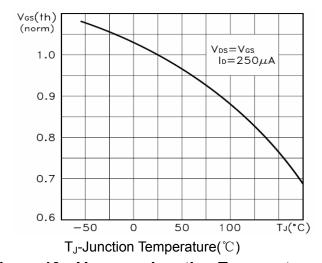


Figure 10 V_{GS(th)} vs Junction Temperature

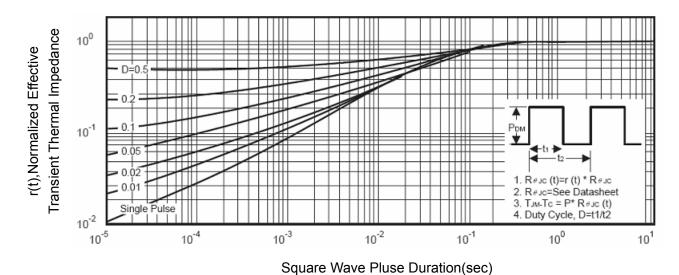
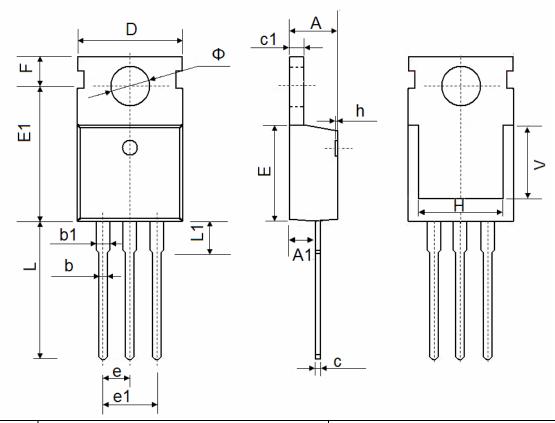


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-220-3L Package Information



Symbol	Dimensions I	n Millimeters	Dimensions In Inches				
Symbol	Min.	Max.	Min.	Max.			
Α	4.400	4.600	0.173	0.181			
A1	2.250	2.550	0.089	0.100			
b	0.710	0.910	0.028	0.036			
b1	1.170	1.370	0.046	0.054			
С	0.330	0.650	0.013	0.026			
c1	1.200	1.400	0.047	0.055			
D	9.910	10.250	0.390	0.404			
E	8.9500	9.750	0.352	0.384			
E1	12.650	12.950	0.498	0.510			
е	2.540	2.540 TYP.		0.100 TYP.			
e1	4.980	5.180	0.196	0.204			
F	2.650	2.950	0.104	0.116			
Н	7.900	8.100	0.311	0.319			
h	0.000	0.300	0.000	0.012			
L	12.900	13.400	0.508	0.528			
L1	2.850	3.250	0.112	0.128			
V	7.500 REF.		0.295 REF.				
Ф	3.400	3.800	0.134	0.150			





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